NSN 6625-00-367-9323

Semiconductor Device Test Set - Page 1 of 1



View Online at https://aerobasegroup.com/nsn/6625-00-367-9323

Inclosure Feature:
Single item w/housing
Test Type For Which Designed:
Measurement of transistors
Functional Classification:
Aa-9.3
Supplementary Features:
Manufacturers name: transistor test set
Shelf Life:
N/a
Unit Of Measure:
Demilitarization:
No

Fiig: T228-a